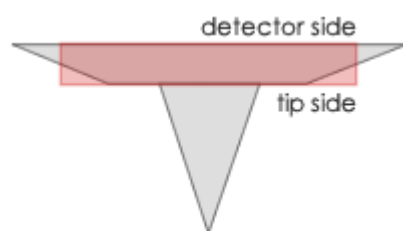


Cantilever Data	Value	Range*
Resonance Frequency	25 kHz	10 - 39 kHz
Force Constant	0.2 N/m	0.02 - 0.7 N/m
Length	225 μm	220 - 230 μm
Mean Width	48 μm	42.5 - 52.5 μm
Thickness	1 μm	0.5 - 1.5 μm

NanoWorld® Pointprobe® CONTSCR AFM probe is an alternative AFM cantilever type for contact mode applications. The length of AFM cantilever is reduced with respect to the preferred contact mode type enabling easier exchange with non-contact mode AFM probes for some AFM instruments. Additionally, this AFM probe type allows the application for lateral or friction force mode.

All SPM probes of the Pointprobe® series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. The AFM tip is shaped like a polygon based pyramid with a typical height of 10 - 15 μm .

Additionally, this AFM probe offers typical AFM tip radius of curvature of less than 8 nm.



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Coating: Reflective Aluminum

Aluminum Reflex Coating

The aluminum reflex coating consists of a 30 nm thick aluminum layer deposited on the

detector side of the AFM cantilever which enhances the reflectance of the laser beam by a factor of 2.5. Furthermore it prevents light from interfering within the AFM cantilever.

As the coating is almost stress-free the bending of the AFM cantilever due to stress is less than 2 degrees.

Order Code	Quantity	Data Sheet
CONTSCR-10	10	yes
CONTSCR-20	20	yes
CONTSCR-50	50	no
CONTSCR-W	380	yes